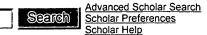


"Hot Carrier Circuit Reliability Simulation"



Scholar

Results 1 - 2 of 2 for "Hot Carrier Circuit Reliability Simulation". (0.09 seconds)

Tip: Try removing quotes from your search to get more results.

A unified compact scalable Δl d model for hot carrier reliability simulation

All articles Recent articles

P Chen, L Wu, G Zhang, Z Liu, BTAT Inc, CA Santa ... - Reliability Physics Symposium Proceedings, 1999. 37th Annual ..., 1999 - ieeexplore.ieee.org

... Section 4 verifies the model accuracy and scalability and shows the result of hot carrier circuit reliability simulation using the new Md model. ...

Cited by 5 - Web Search

<u>Implementation of hot-carrier reliability simulation in Eldo</u>

M Karam, W Fikry, H Haddara, H Ragai - Circuits and Systems, 2001. ISCAS 2001. The 2001 IEEE ..., 2001 - ieeexplore.ieee.org

... Section 4 verifies the model accuracy and continuity and shows the results of hot-carrier circuit reliability simulation on some practical applications. ... Cited by 3 - Web Search - BL Direct

"Hot Carrier Circuit Reliability Simul



Google Home - About Google - About Google Scholar

@2006 Google

	Туре	L#	Hits	Search Text	DBs	Time Stamp
	BRS	L1	23528	((functional adj blocks) same circuit\$2)	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:22
2	BRS	L2	252		US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:24
3	BRS	L3	17		US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:51
4	BRS	L4	2	((functional adj blocks) same circuit\$2) and (first adj device) and (second adj device) and (first adj set) and (second adj set) and leakage	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:25
5	BRS	L5	33		US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:28

	Туре	L#	Hits	Search Text	DBs	Time Stamp
6	BRS	L6	7	(simulation same (single adj run)) and quant\$3	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:30
7	BRS	L7	2	(simulation same (single adj run)) and leakage and drain	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:30
8	BRS	L8	o	(simulation same (single adj run)) and leakage and drain and transconduct	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:30
9	BRS	L9	2	(simulation same (single adj run)) and transconductance	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:42
10	BRS	L10	2	(simulation same (single adj run)) and transconductance and data and test	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:42

	Туре	L#	Hits	Search Text	DBs	Time Stamp
11	BRS	L11	282	((functional adj blocks) same circuit\$2) and (different adj functional adj blocks)	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 16:52
12	BRS	L12	3	((functional adj blocks) same circuit\$2) and (different adj functional adj blocks) and (performance same criteria)	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 17:24
13	BRS	L13	322	(circuit adj degradation)	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 17:24
14	BRS	L14	5	(circuit adj degradation) and (first adj set) and (second adj set)	US- PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	2006/05/20 17:25